N-Channel Power MOSFET 600 V, 3.6 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V_{DSS}	600		٧
Continuous Drain Current R _{θJC}	I _D	3.1 (Note 1)	2.6	Α
Continuous Drain Current $R_{\theta JC}$ $T_A = 100^{\circ}C$	I _D	2.9 (Note 1)	1.65	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	12	10	Α
Power Dissipation $R_{\theta JC}$	P_{D}	27	61	W
Gate-to-Source Voltage	V _{GS}	±30)	V
Single Pulse Avalanche Energy, I _D = 3.0 A	E _{AS}	100 3000		mJ
ESD (HBM) (JESD 22-A114)	V _{esd}			V
RMS Isolation Voltage (t = 0.3 sec., R.H. ≤ 30%, T _A = 25°C) (Figure 17)	V _{ISO}	4500		٧
Peak Diode Recovery (Note 2)	dv/dt	4.5	l	V/ns
Continuous Source Current (Body Diode)	I _S	3.0 260 -55 to 150		Α
Maximum Temperature for Soldering Leads	TL			°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}			°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Limited by maximum junction temperature
- 2. $I_{SD} = 3.0 \text{ A}$, di/dt $\leq 100 \text{ A/}\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, $T_{J} = +150^{\circ}\text{C}$

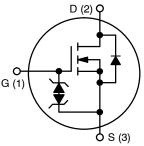


ON Semiconductor®

www.onsemi.com

V _{DSS}	R _{DS(on)} (MAX) @ 1.2 A
600 V	3.6 Ω

N-Channel





NDF03N60ZG, NDF03N60ZH TO-220FP CASE 221AH



NDD03N60Z-1G IPAK CASE 369D



NDD03N60ZT4G DPAK CASE 369AA

MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information on page 7 of this data sheet.

THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF03N60Z NDD03N60Z	$R_{ heta JC}$	4.7 2.0	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF03N60Z (Note 4) NDD03N60Z (Note 3) NDD03N60Z-1	$R_{ hetaJA}$	51 40 80	

^{3.} Insertion mounted

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

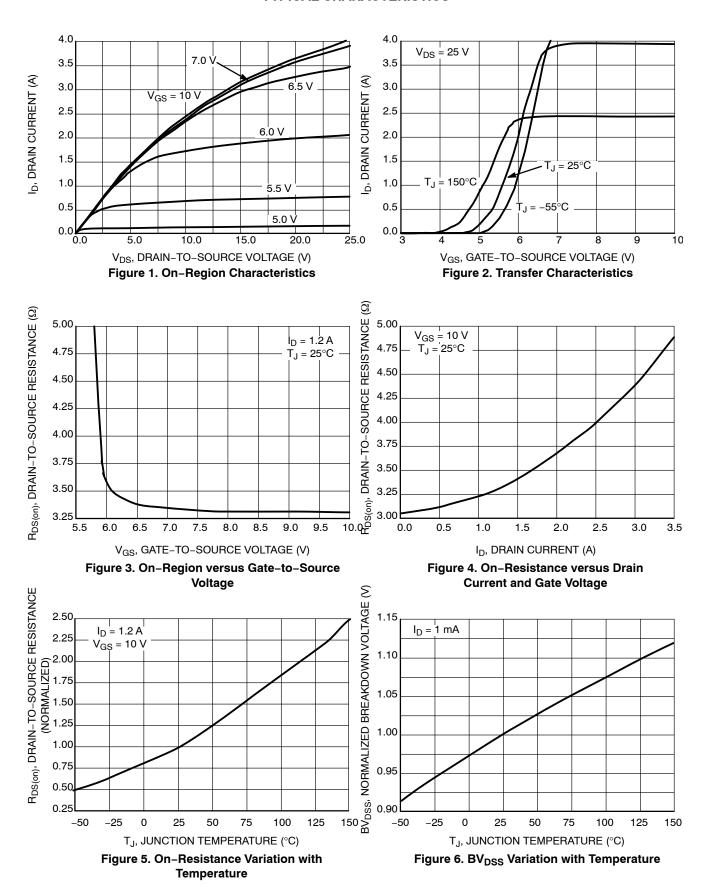
Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					-	-	-
Drain-to-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 1 mA		BV _{DSS}	600			V
Breakdown Voltage Temperature Co- efficient	Reference to 25°C, $I_D = 1 \text{ mA}$		$\Delta BV_{DSS}/ \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V _{DS} = 600 V, V _{GS} = 0 V	25°C 150°C	I _{DSS}			1 50	μΑ
Gate-to-Source Forward Leakage	V _{GS} = ±20 V	<u> </u>	I _{GSS}			±10	μА
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 1.2 \text{ A}$	A	R _{DS(on)}		3.3	3.6	Ω
Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 50 μ	4	V _{GS(th)}	3.0	3.9	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 1.5 A	A	9FS		2.0		S
DYNAMIC CHARACTERISTICS							
Input Capacitance (Note 6)	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}	248	312	372	pF
Output Capacitance (Note 6)			C _{oss}	30	39	50	
Reverse Transfer Capacitance (Note 6)			C _{rss}	4	8	12	
Total Gate Charge (Note 6)			Qg	6	12	18	nC
Gate-to-Source Charge (Note 6)			Q_{gs}	1.5	2.5	4	
Gate-to-Drain ("Miller") Charge (Note 6)	$V_{DD} = 300 \text{ V}, I_D = 3.0 \text{ V}$ $V_{GS} = 10 \text{ V}$	А,	Q_{gd}	3	6.1	9	
Plateau Voltage			V _{GP}		6.4		V
Gate Resistance			Rg		6.0		Ω
RESISTIVE SWITCHING CHARACTERI	STICS						
Turn-On Delay Time			t _{d(on)}		9		ns
Rise Time	V _{DD} = 300 V, I _D = 3.0 A	Α,	t _r		8		
Turn-Off Delay Time	$V_{DD} = 300 \text{ V}, I_D = 3.0 \text{ A}$ $V_{GS} = 10 \text{ V}, R_G = 5 \text{ C}$	2	t _{d(off)}		16		
Fall Time			t _f		10		
SOURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless oth	erwise note	ed)				
Diode Forward Voltage	I _S = 3.0 A, V _{GS} = 0 V	′	V_{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30 V	/	t _{rr}		265		ns
Reverse Recovery Charge	$I_S = 3.0 \text{ A}, \text{ di/dt} = 100 \text{ A}$	/μs	Q _{rr}		0.9		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

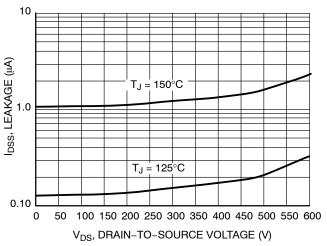
^{4.} Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).

^{5.} Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
6. Guaranteed by design.

TYPICAL CHARACTERISTICS



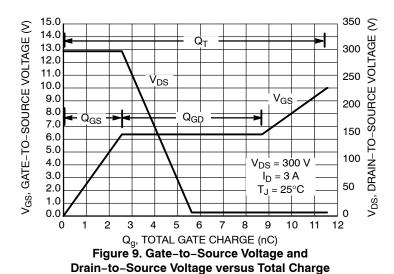
TYPICAL CHARACTERISTICS

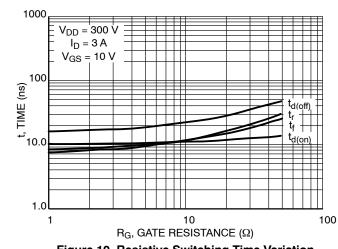


700 $T_{J}^{1} = 25^{\circ}C$ 650 $V_{GS} = 0 V$ f = 1 MHz 600 550 CAPACITANCE (pF) 500 450 400 350 C_{iss} 300 250 200 Ú 150 100 Coss 50 0 0 5 15 20 25 30 35 40 45 50 V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation





10.0 (V) T_J = 150°C 1.0 1.0 1.0 1.0 1.0 1.0 0.1 0.3 0.4 0.5 0.6 0.7 0.8 0.9 1.0 1.1 1... V_{SD}, SOURCE-TO-DRAIN VOLTAGE (V)

Figure 10. Resistive Switching Time Variation versus Gate Resistance

Figure 11. Diode Forward Voltage versus Current

TYPICAL CHARACTERISTICS

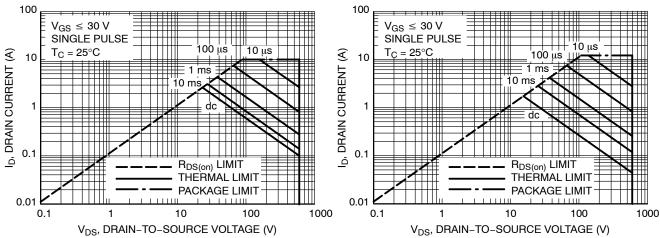


Figure 12. Maximum Rated Forward Biased Safe Operating Area NDD03N60Z

Figure 13. Maximum Rated Forward Biased Safe Operating Area NDF03N60Z

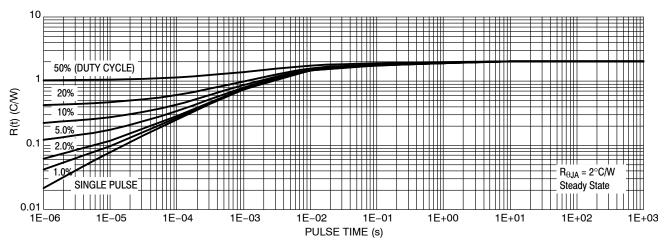


Figure 14. Thermal Impedance (Junction-to-Case) for NDD03N60Z

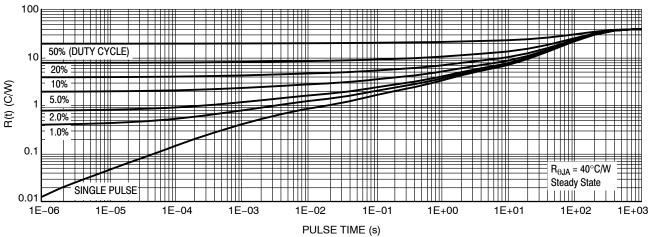


Figure 15. Thermal Impedance (Junction-to-Ambient) for NDD03N60Z

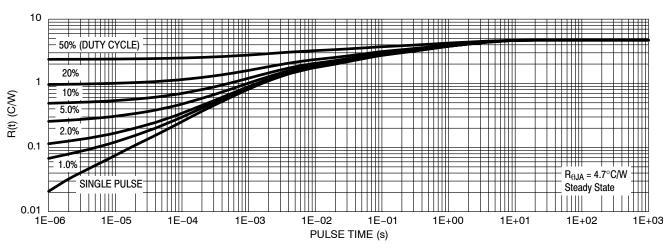


Figure 16. Thermal Impedance (Junction-to-Case) for NDF03N60Z

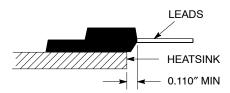


Figure 17. Isolation Test Diagram

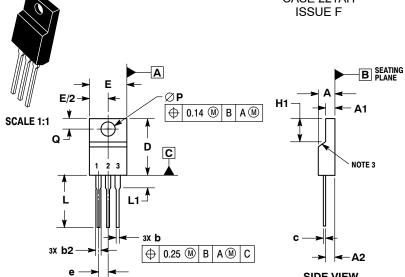
Measurement made between leads and heatsink with all leads shorted together.

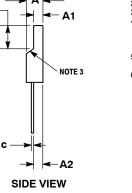
*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.



ISSUE F

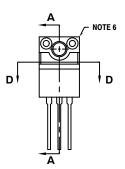
DATE 30 SEP 2014

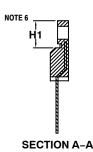






FRONT VIEW





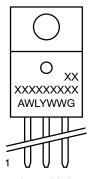
ALTERNATE CONSTRUCTION

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. CONTOUR UNCONTROLLED IN THIS AREA.
- CONTOUR ONCOUNT HOLLED IN THIS AREA.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.
 DIMENSION b2 DOES NOT INCLUDE DAMBAR PROTRUSION.
 LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.
- CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS AT AND H1 FOR MANUFACTURING PURPOSES.

THE THE COLUMN WOLLD					
	MILLIMETERS				
DIM	MIN	MAX			
Α	4.30	4.70			
A1	2.50	2.90			
A2	2.50	2.90			
b	0.54	0.84			
b2	1.10	1.40			
С	0.49	0.79			
D	14.70	15.30			
E	9.70	10.30			
е	2.54	BSC			
H1	6.60	7.10			
L	12.50	14.73			
L1		2.80			
P	3.00	3.40			
Q	2.80	3.20			

GENERIC MARKING DIAGRAM*



= Assembly Location

WL = Wafer Lot

= Year

WW = Work Week

G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLE 1:		STYLE 2:	
PIN 1.	MAIN TERMINAL 1	PIN 1.	CATHODE
2.	MAIN TERMINAL 2	2.	ANODE
3.	GATE	3.	GATE

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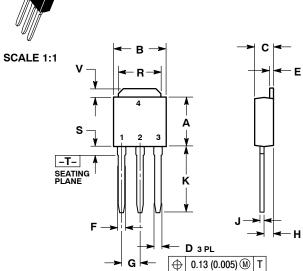
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MECHANICAL CASE OUTLINE





DATE 15 DEC 2010



STYLE 2:

PIN 1. GATE

3

STYLE 6: PIN 1. MT1 2. MT2 3. GATE

2. DRAIN

4. DRAIN

MT2

SOURCE

STYLE 1: PIN 1. BASE

3

STYLE 5: PIN 1. GATE

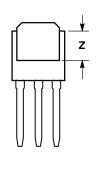
2. ANODE 3. CATHODE

ANODE

2. COLLECTOR

EMITTER

COLLECTOR



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.35	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
E	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.090	BSC	2.29 BSC		
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.350	0.380	8.89	9.65	
R	0.180	0.215	4.45	5.45	
S	0.025	0.040	0.63	1.01	
٧	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

MARKING DIAGRAMS

STYLE 3: PIN 1. ANODE

2. CATHODE

4. CATHODE

3 ANODE

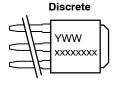
STYLE 7: PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

STYLE 4: PIN 1. CATHODE ANODE
 GATE

4. ANODE

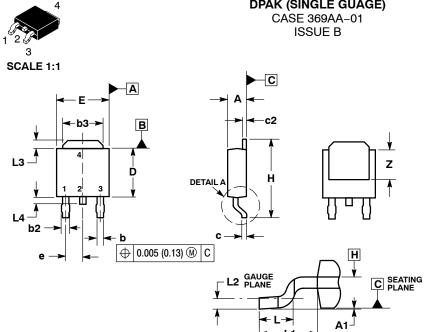




xxxxxxxxx = Device Code Α = Assembly Location IL = Wafer Lot Υ = Year WW = Work Week

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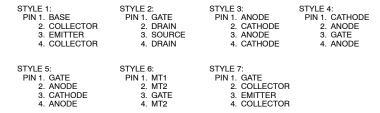


DETAIL A ROTATED 90° CW **DATE 03 JUN 2010**

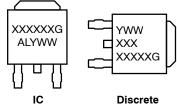
NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74	REF
L2	0.020 BSC		0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



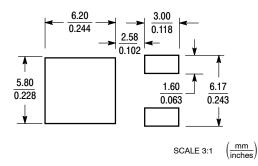
GENERIC MARKING DIAGRAM*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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